Contribution ID: 16 Type: Short talk

## Contribution of Instrument control to higher throughput at instruments

Monday, 19 June 2023 16:30 (20 minutes)

The beam time at each of the MLZ instruments is limited. Therefore we should look around for ways to increase the proposals running at the instruments or measure more samples during a measurement session or perform more scans in the same time.

All solution require a higher automation of the measurement process. The goal has to be, give the users more (even preliminary) results in shorter times.

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